

Form PTO-1449 U.S. Department of Commerce  
(REV. 2-82) Patent and Trademark Office

Atty. Docket No.  
036179/US/2-475387-30

Serial No.  
10/577,562

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**  
(Use several sheets if necessary)

Applicant(s)  
Seok-Hyun Yun et al.

Filing Date  
April 27, 2006

Confirmation No.  
3634

**U.S. PATENT DOCUMENTS**

*Exam. Init.	Document No.							Date	Name	Class	Subclass	Filing Date if Appropriate
	6	0	2	0	9	6	3	February 1, 2000	Dimarzio et al ΩΩΩΩΩ			
	6	3	4	1	0	3	6	January 22, 2002	Tearney et al. ΩΩΩΩΩΩ			
	6	3	9	6	9	4	1	May 28, 2002	Bacus, James W. et al. ΩΩΩΩΩΩΩ			
200	5	0	1	8	2	0	1	January 27, 2005	De Boer, Johannes F. Et al ΩΩΩΩΩΩΩΩ			
	6	5	6	7	5	8	5	May 20, 2003	Martin et al ΩΩΩΩΩΩΩΩ			
	5	9	2	6	5	9	2	July 20, 1999	Martin et al. ΩΩΩΩΩΩΩΩ			
	7	2	6	7	4	9	4	September 11, 2007	Hongyu et al. ΩΩΩΩΩΩΩΩ			
	5	9	7	5	6	9	7	November 2, 1999	Podoleanu et al.			
	5	2	4	1	3	6	4	August 31, 1993	Kimura et al. ΩΩΩΩΩΩΩΩΩΩ Ω			
	5	9	1	0	8	3	9	June 8, 1999	Erskine et al ΩΩΩΩΩΩΩΩΩΩ Ω			
200	7	0	7	0	4	9	6	March 29, 2007	Gweon et al. ΩΩΩΩΩΩΩΩΩΩ Ω			
	4	8	2	7	9	0	7	May 9, 1989	Tashiro et al. ΩΩΩΩΩΩΩΩΩΩ ΩΩ			
	4	9	9	8	9	7	2	March 12, 1991	Chin et al. ΩΩΩΩΩΩΩΩΩΩ ΩΩ			
	5	7	3	0	7	3	1	March 24, 1998	Mollenauer et al. ΩΩΩΩΩΩΩΩΩΩ ΩΩ			

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	200	3	1	2	0	1	3	7	June 26, 2003	Pawluczyk et al VV			
	200	2	0	9	1	3	2	2	July 11, 2002	Chaiken et al. VV			
	2005	0	1	6	5	3	0	3	July 28, 2005	Kleen Martin et al. VVV			
	200	2	0	5	2	5	4	7	May 2, 2002	Toida Masahiro VVV			
	200	4	0	0	2	6	5	0	January 1, 2004	Mandrusov Evgenia et al. VVV			
	200	3	0	8	2	1	0	5	May 1, 2003	Fischman, Alan et al. VVV			
		5	3	0	4	1	7	3	April 19, 1994	Kittrell, Carter et al. VVV			
		7	3	3	6	3	6	6	February 26, 2008	Choma et al.			
		7	0	1	9	8	3	8	March 28, 2006	Izatt et al.			
		6	3	7	4	1	2	8	April 16, 2002	Toida et al.			
		6	4	7	7	4	0	3	November 5, 2002	Eguchi et al.			
		5	5	5	5	0	8	7	September 10, 1996	Miyagawa et al. VVVV			
	200	5	0	5	7	7	5	6	March 17, 2005	Fang-Yen et al. VVV			
		4	5	8	5	3	4	9	April 29, 1986	Gross Daniel et al.			
		5	7	8	5	6	5	1	July 28, 1998	Baker et al. VVVVV			

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		5	8	1	7	1	4	4	October 6, 1998	Gregory Kenton et al. <u>YYYYYY</u>			
	2003	0	1	7	4	3	3	9	September 18, 2003	Feldchtein et al.			
	200	3	0	3	0	8	1	6	February 13, 2003	Eom Tae Bong et al.			
	200	2	0	5	7	4	3	1	May 16, 2002	Fateley William G. et al			
	2005	0	0	5	7	6	8	0	March 2005	Agan, Martin J. <u>YYYYYY</u>			
		5	3	4	8	0	0	3	September 1994	Caro, Richard G. <u>YYYYYY</u>			
		5	2	5	0	1	8	6	October 1993	Dollinger et al. <u>YYYYYY</u>			
		5	3	9	4	2	3	5	February 1995	Takeuchi et al. <u>YYYYYY</u>			
		6	2	4	9	3	8	1	June 2001	Suganuma, Hiroshi <u>YYYYYY</u>			
		6	9	0	9	1	0	5	June 2005	Heintzmann et al. <u>YYYYYY</u>			
		7	2	3	6	6	3	7	June 2007	Sirohey et al. <u>YYYYYY</u>			
	2002	0	0	4	8	0	2	5	April 2002	Takaoka, Hideyuki $\epsilon$			
	2002	0	1	6	8	1	5	8	November 2002	Furusawa et al. $\epsilon\epsilon$			
		6	7	5	7	4	6	7	June 2004	Rogers, Philip L. $\epsilon\epsilon$			
		5	5	6	6	2	6	7	October 1996	Neuberger, Wolfgang			

## FOREIGN PATENT DOCUMENT

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		Document No.							Date	Country	Class	SubClass	Translator Yes No
		7	9	0	0	8	4	1					
		9	8	0	0	0	5	7	January 8, 1998	WIPO ΩΩΩ			
200	2	0	8	4	2	6	3		October 24, 2002	WIPO ΩΩΩΩΩΩ			
200	4	0	5	7	2	6	6		July 8, 2004	WIPO ΩΩΩΩΩΩ			
200	1	0	2	7	6	7	9		April 19, 2001	WIPO ΩΩΩΩΩΩΩΩ			
200	3	0	4	6	6	3	6		June 5, 2003	WIPO ΩΩΩΩΩΩΩΩ			
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	9	2	0	1	9	6	6		February 6, 1992	WIPO¥			
	6	0	7	3	4	0	5		April 25, 1985	Japan¥			
	5	5	0	9	4	1	7		November 22, 1993	Japan¥			
	2	7	3	8	3	4	3		August 30, 1995	France¥			
200	3	0	6	2	8	0	2		July 31, 2003	WIPO			
200	5	0	4	7	8	1	3		May 26, 2005	WIPO			
	2	2	9	8	0	5	4		August 21, 1996	Great BritainYYYY			
200	6	1	2	4	8	6	0		November 23, 2006	WIPO YYYY			
200	2	2	1	4	1	2	7		July 31, 2002	JapanYYYY¥			
	0	1	0	1	1	1	1		January 2001	WIPO €€			

<sup>a</sup>Reference cited in Office Action dated October 1, 2008 for U.S. Patent Application No. 11/955,986

YYYY European Search Report issued May 5, 2009 for European Application no. 01991471.2

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XXXXXX Reference cited in Notice of Reasons for Reject dated July 14, 2009 for Japanese Application No. 2006-503161

XXXXXX Reference cited in Office Action dated August 18, 2009 for U.S. Patent application no. 12/277,178

XXXXXX Reference cited in Office Action dated August 13, 2009 for U.S. Patent application no. 10/136,813

XXXXXX Reference cited in Office Action dated August 6, 2009 for U.S. Patent application no. 11/624,455

XXXXXX Reference cited in Office Action dated May 15, 2009 for U.S. Patent application no. 11/537,123

€ Reference cited in Office Action dated April 17, 2009 for U.S. Patent application no. 11/537,343

€€ Reference cited in Office Action dated April 15, 2009 for U.S. Patent application no. 12/205,775

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		Copy of International Search Report and Written Opinion for PCT/US2007/081982 dated October 19, 2007
		Database Compindex Engineering Information, Inc., New York, NY, US; March 5, 2007, Yelin, Dvir et al: "Spectral-Domain Spectrally-Encoded Endoscopy" ΩΩ
		Database Biosis Biosciences Information Service, Philadelphia, PA, US; October 2006, Yelin D. et al: "Three-Dimensional Miniature Endoscopy" ΩΩ
		Copy of International Search Report and Written Opinion mailed March 14, 2005 for PCT/US2004/018045
		Copy of Notification of the international Preliminary Report on Patentability mailed October 21, 2005
		Shim M.G. et al., "Study of Fiber-Optic Probes For In vivo Medical Raman Spectroscopy" Applied Spectroscopy, Vol. 53, No. 6, June 1999 ΩΩΩ
		Bingid U. et al., "Fibre-Optic Laser-Assisted Infrared Tumour Diagnostics (FLAIR); Infrared Tumour Diagnostics" Journal of Physics D. Applied Physics, Vol. 38, No. 15, August 7, 2005 ΩΩΩ
		Jun Zhang et al. "Full Range Polarization-Sensitive Fourier Domain Optical Coherence Tomography" Optics Express, Vol. 12, No. 24, November 29, 2004 ΩΩΩΩ
		Yonghua et al., "Real-Time Phase-Resolved Functional Optical Hilbert Transformation" Optics Letters, Vol. 27, No. 2, January 15, 2002 ΩΩΩΩ

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		Siavash et al., "Self-Referenced Doppler Optical Coherence Tomography" Optics Letters, Vol. 27, No. 23, December 1, 2002
		Copy of International Search Report and Written Opinion dated December 20, 2004 for PCT/US04/10152
		Copy of Notification Concerning Transmittal of Copy of International Preliminary Report on Patentability dated October 13, 2005 for PCT/US04/10152
		Copy of International Search Report and Written Opinion dated March 23, 2006 for PCT/US2005/042408
		Copy of International Preliminary Report on Patentability dated June 7, 2007 for PCT/US2005/042408
		Copy of International Search Report and Written Opinion dated February 28, 2007 for International Application No. PCT/US2006/038277
		Copy of International Search Report and Written Opinion dated January 30, 2009 for International Application No. PCT/US2008/081834
		Copy of International Search Report and Written Opinion dated February 2, 2009 for International Application No. PCT/US2008/071786
		Bilenca A et al: "The Role of Amplitude and phase in Fluorescence Coherence Imaging: From Wide Filed to Nanometer Depth Profiling", <i>Optics IEEE</i> , May 5, 2007
		Inoue, Yusuke et al: "Variable Phase-Contrast Fluorescence Spectrometry for Fluorescently Strained Cells", <i>Applied Physics Letters</i> , September 18, 2006
		Bernet, S et al: "Quantitative Imaging of Complex Samples by Spiral Phase Contrast Microscopy", <i>Optics Express</i> , May 9, 2006
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		Copy of Office Action dated February 17, 2009 for U.S. Patent application no. 11/211,483
		Copy of Notice of Reasons for Rejection mailed December 2, 2008 for Japanese patent application no. 2000-533782
		Copy of International Search Report and Written Opinion dated February 24, 2009 for PCT/US2008/076447
		Copy of European Official Action dated December 2, 2008 for EP 07718117.0
		Barfuss et al (1989) "Modified Optical Frequency Domain Reflectometry with High spatial Resolution for Components of integrated optic Systems", Journal of Lightwave Technology, IEEE Vol 7., No. 1
		Yun et al., (2004) "Removing the Depth-Degeneracy in Optical Frequency Domain Imaging with Frequency Shifting", Optics Express, Vol. 12, No. 20
		Copy of International Search Report and Written Opinion dated June 10, 2009 for PCT/US08/075456
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		Motz, J.T. et al: "Spectral-and Frequency-Encoded Fluorescence Imaging" Optics Letters, OSA, Optical Society of America, Washington, DC, US, vol. 30, no. 20, October 15, 2005, pages 2760-2762
		Copy of Japanese Notice of Reasons for Rejection dated July 14, 2009 for Japanese Patent application no. 2006-503161
		Copy of Office Action dated August 18, 2009 for U.S. patent application no 12/277,178
		Copy of Office Action dated August 13, 2009 for U.S. patent application no. 10/136,813

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		Copy of Office Action dated April 17, 2009 for U.S. patent application no. 11/537,343
		Copy of Office Action dated April 15, 2009 for U.S. patent application 12/205,775

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